

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/822,145	YANG ET AL.	
Examiner	Art Unit	
RATIAIN	2416	

	SEARCHED		
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Uspgpub,uspat,usocr,fprs,epo,jpo,der went,ibm_tdm inventor search	2/25/2008	RJ
370/229-235*,237,412,413,468	3/9/2008	RJ